



AH4930Q

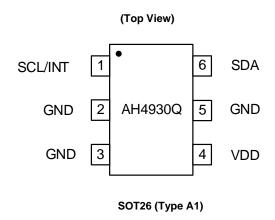
AUTOMOTIVE 3D MAGNETIC LINEAR HALL SENSOR WITH I2C INTERFACE

Description

The AH4930Q automotive 3D magnetic chip is a miniature monolithic sensor IC sensitive to the three orthogonal components of the flux density applied to the IC. On-chip integrated temperature sensor data is available for system functions such as junction temperature indication and temperature compensation of magnetic field measurement. A precision analog signal-path along with integrated ADC digitizes the measured analog magnetic field values, and this allows the AH4930Q with the correct magnetic circuit to decode the absolute position of any moving magnet. With its magnetic field detection in x, y, and z-direction the sensor reliably measures threedimensional, linear and rotation movements.

The AH4930Q measurement data can be read over I2C bus. The sensor is runtime programmable and offers on-chip temperature compensation of the measured units. The selectable power mode control unit enables micro-power and continuous measurement functionality. Applications include joysticks, control elements (white goods, multifunction knops), or electric meters (anti-tampering) and any other application that requires accurate angular measurements or low power consumptions.

Pin Assignments



Features

- 3D magnetic flux density sensing
- Low power-down current 9nA typical
- Very low power consumption = 13µA during operation (10Hz,
- Digital output via standard I²C interface up to 1 Mbit/sec
- 12-bit data resolution for each measurement direction
- Bx, By and Bz linear field measurement up to +-1300Gs
- Different power modes and variable update frequencies
- Supply voltage range = 2.8V to 5.5V, temperature range T_J = -40°C to +125°C
- Small, industrial 6-pin SOT26 (Type A1) package
- Interrupt signal available to wake up a microcontroller to save system power and watch dog in wake-up mode
- Temperature measurement
- Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)
- The AH4930Q is suitable for automotive applications requiring specific change control; this part is AEC-Q100 qualified, PPAP capable, and manufactured in IATF16949 certified facilities.

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Applications

- Knobs/levers
- Joysticks with push
- Rotaries with push
- Linear (long strokes)
- Stalk gear shifters
- Shifter position sensors
- Robotics shaft positions
- Flap positions
- Mirror positions
- Flow meters
- Load detection
- Water levels
- Multimedia rotaries/push selectors
- Door handles & door locks
- Motor commutation
- Power tools (speed, torque, direction selections)
- 2-wheelers (throttle controls, multifunction switchgears)

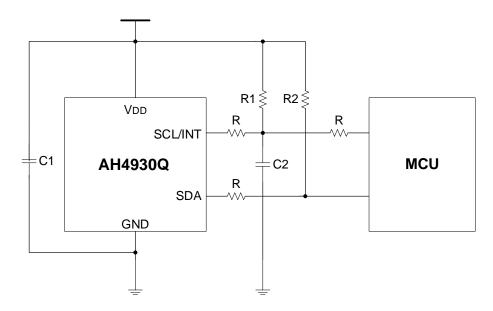
Notes:

- 1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS), 2011/65/EU (RoHS 2) & 2015/863/EU (RoHS 3) compliant.
- 2. See https://www.diodes.com/quality/lead-free/ for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + CI) and <1000ppm antimony compounds.

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Typical Applications Circuit (Note 4)



Note: 4. C1 = 100nF, $R1/R2 = 1.2k\Omega$ are recommended by Diodes Incorporated. R/C2 values are dependent on capability of noise immunity.

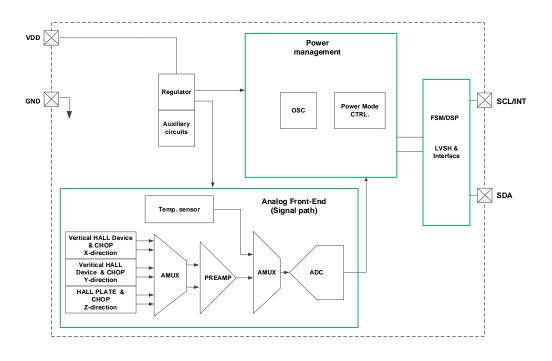
Pin Descriptions

Package: SOT26 (Type A1)

| Pin Number | Pin Name | I/O | Function |
|------------|----------|--------|-------------------------------------|
| 1 | SCL/INT | I/O | Bus clock, also used as INT output. |
| 2 | GND | Ground | IC ground |
| 3 | GND | Ground | Not used, should be Grounded. |
| 4 | VDD | Power | Power |
| 5 | GND | Ground | Not used, should be Grounded. |
| 6 | SDA | I/O | Bus data |



Functional Block Diagram



Absolute Maximum Ratings (Note 5) (@TA = +25°C, 10G = 1mT, unless otherwise specified.)

| Symbol | Parameter | | Value | Unit |
|----------------------|---|-----------------|-------------|------|
| V _{DD} | Supply Voltage (Notes 5, 6) | | 6 | ٧ |
| V _{DD_} REV | Reverse Supply Voltage | | -0.3 | V |
| SDA, SCL | Voltage on SDA, SCL | | -0.3 to +6 | V |
| В | Magnetic Flux Density | | 10000 | G |
| PD | Package Power Dissipation (Note 7) | SOT26 (Type A1) | 1150 | mW |
| T _{STG} | Storage Temperature Range | | -65 to +125 | °C |
| TJ | Maximum Junction Temperature | | +150 | °C |
| ESD | Human Body Model ESD Capability (Note 8) | | 2 | kV |
| ESD | Charge Device Model ESD Capability (Note 8) | | 1000 | V |

Notes:

- 5. Stresses greater than those listed under *Absolute Maximum Ratings* can cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions* is not implied. Exposure to *Absolute Maximum Ratings* for extended periods can affect device reliability.
- 6. The absolute maximum V_{DD} of 6V is a transient stress rating and is not meant as a functional operating condition. It is not recommended to operate the device at the absolute maximum rated conditions for any period of time.
- 7. Device mounted on the JEDEC High-K board. 3 inch x 3 inch with 1oz. Internal power and ground planes and 2oz. copper traces on the top and bottom of the board.
- 8. This device is ESD sensitive.



Recommended Operating Conditions (@TA = +25°C, unless otherwise specified.)

| Symbol | Parameter | Conditions | Rating | Unit |
|----------|-----------------------------|------------|-------------|------|
| V_{DD} | Supply Voltage | Operating | 2.8 to 5.5 | V |
| TJ | Operating Temperature Range | Operating | -40 to +125 | °C |

Electrical Characteristics (V_{DD} = 3.3V @T_A = +25°C, unless otherwise specified.)

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|----------------------------------|--|---|-----|-----------------|------|-----------------|
| V _{DD} | Supply voltage | _ | 2.8 | 3.3 | 5.5 | V |
| tpup | Power-up ramp time | V _{DD} rising from 0 to 90% of V _{DD} | _ | _ | 10 | μs |
| tinit | Sensor initialization time | Power-up reset to first I ² C cycle | 500 | _ | _ | μs |
| Vous | Power-up over-undershoot | Envelope which must not be exceeded at the end of a power-up | 3 | 3.3 | 3.5 | V |
| Vuvlo | Reset level (UVLO) | V _{DD} rising to start conversion | | 2.5 | _ | V |
| Vuvlo_HYS | Reset level_hysteresis (UVLO) | VuvLo (VIN falling to stop conversion) | | 0.1 | _ | V |
| IDD(ULMP) | IDD in duty cycled operation average current | Ultra low-power mode | _ | 13 (10Hz) | _ | μA |
| I _{DD(LPM)} | I _{DD} in duty cycled operation average current | Low-power mode | _ | 95 (83.3Hz) | _ | μΑ |
| IDD(FSM) | IDD in continuous operation average current | Fast mode | _ | 3.8 (3.3kHz) | _ | mA |
| I _{DD(POWER} - DOWN) | I _{DD} in power-down mode | IC is in power-down condition | 1 | 9 | _ | nA |
| VIL | Input low threshold voltage | All input pins | ı | _ | 0.3 | V _{DD} |
| Vih | Input high threshold voltage | All input pins | 0.7 | _ | _ | V _{DD} |
| V _{I_HYS} | Input hysteresis voltage | All input pins | - | 0.05 | _ | V |
| Vol | Output low level | Vol (@3mA) | | _ | 0.4 | V |
| Voн | Output high level | Given by ext. pullup resistor $1.2k\Omega$ | ı | V _{DD} | _ | V |
| ILEAKAGE | ILEAKAGE when pin disabled | SDA, SCL | - | _ | 0.1 | μA |
| T _{RANGE} | Temp. sensor (range) | _ | -40 | _ | +125 | °C |
| T ₂₅ | Temp. sensor +25°C code | T _A = +25°C | _ | 25 | _ | LSB |
| Tres | Temp. sensor (resolution 12bits) | _ | _ | 1 | _ | °C /LSB |
| T _{ACC} | Temp. sensor (accuracy) | T _A = +25°C | _ | +/-10 | _ | °C |
| fur | Update rate X, Y, Z | Max. conversion rate (Fast mode) | _ | 3.3k | _ | Hz |
| fur_Lp | Update rate (Low power) | INT. triggered rate in LPM | _ | 83.3 | _ | Hz |
| fur_ulp | Update rate (Ultra LP) | INT. triggered rate in ULPM | _ | 10 | _ | Hz |
| tclk_E | Clock freq. drift | Freq. shift of int. clock (T _A = -40°C to +125°C) | -20 | 0 | 20 | % |
| tint | End of conversion (INT pulse) | Low active pulse width | 1.5 | 2 | _ | μs |



Timing Requirements for I²C:

| Comple al | Davana et a s | 400 | kHz (Fast Mo | ode) | 1000 | kHz (Fast Mo | ode+) | l lmit |
|------------------|--|-----|--------------|------|------|--------------|-------|--------|
| Symbol | Parameter | Min | Тур | Max | Min | Тур | Max | Unit |
| f _{SCL} | I ² C clock frequency | _ | _ | 400 | _ | _ | 1000 | kHz |
| t∟ | Clock low time | 1.3 | _ | _ | 0.5 | _ | _ | μs |
| tн | Clock high time | 0.6 | _ | _ | 0.4 | _ | _ | μs |
| tsta | Hold time for a (repeated) START condition | 0.6 | _ | _ | 0.4 | _ | _ | μs |
| tstop | Setup time for STOP condition | 0.6 | _ | | 0.4 | _ | _ | μs |
| tsu | Data setup time | 0.1 | _ | _ | 0.1 | _ | _ | μs |
| tHOLD | Data hold time | 0 | _ | _ | 0 | _ | _ | μs |
| trise | Rise time of SDA and SCL (Note 9) | _ | _ | 0.5 | _ | _ | 0.5 | μs |
| tFALL | Fall time of SDA and SCL (Note 9) | _ | _ | 0.3 | _ | 0.25 | 0.3 | μs |
| twait | Bus free time between a STOP and a START condition | 0.6 | _ | - | 0.4 | _ | _ | μs |

Note: 9. Dependent on used R-C combination. For applications, total capacitive load should be < 200 pF.

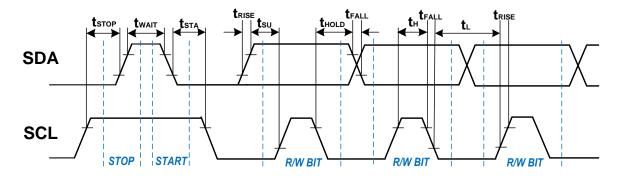


Figure 1. I²C Timing Parameters



Magnetic Characteristics (Notes 10 and 11) (T_A = +25°C, V_{DD} = 3.3V, unless otherwise specified.)

Standard convention for representing the direction of magnetic field strength and flux density by positive and negative signs is as follows:

A positive field is considered as South-Pole facing the corresponding Hall element and Figure 2 shows the definition of magnetic directions X, Y, Z of the AH4390Q

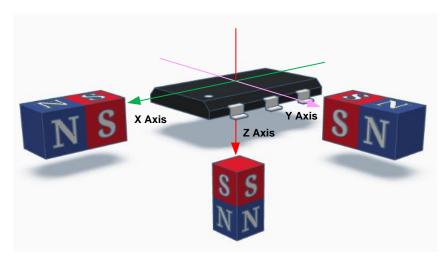


Figure 2. Definition of Magnetic Field Direction

(V_{DD} = 3.3V @T_A = +25°C, unless otherwise specified. Magnetic range = +-1300 Gauss)

| Symbol | Parameter | Condition | Min | Тур | Max | Unit |
|--------------------|--------------------------------|------------|-----|---------|-----|-------|
| Bxyz_lin (Note 12) | Usable linear magnetic range | Bx, By, Bz | _ | +/-1300 | _ | Gauss |
| Bo_xy | Offset | Bx, By | -15 | +-2 | 15 | Gauss |
| Bo_z | Offset | Bz | -10 | +-2 | 10 | Gauss |
| Sx, Sy, Sz | Sensitivity X, Y, Z | Bx, By, Bz | _ | 1 | _ | LSB/G |
| Res12 | Resolution 12bit | _ | _ | 1 | _ | G/LSB |
| Bn | Magnetic noise (rms = 1 sigma) | Bx, By, Bz | 1 | 1 | 1 | Gauss |

Notes:

- 10. Typical data is at $T_A = +25$ °C, $V_{DD} = 3.3$ V.
- 11. Maximum and minimum parameter values over operating temperature range are not tested in production; they are guaranteed by design. The magnetic characteristics may vary with supply, operating temperature and after soldering.

 12. Not subject to production test, verified by design/characterization.



Magnetic Characteristics (V_{DD} = 3.3V @T_A = -40°C to +125°C, unless otherwise specified.)

| Symbol | Parameter | Condition | Min | Тур | Max | Unit |
|-------------------|----------------------------------|-------------|-----|-------|-----|-------|
| SxD, SyD, SzD | Sensitivity drift | Sx, Sy, Sz | _ | +/-20 | _ | % |
| Bo_D_xy (Note 12) | Offset drift | Bx, By @0Gs | -15 | +/-2 | +15 | Gauss |
| Bo_D_z (Note 12) | Offset drift | Bz @0Gs | -10 | +/-2 | +10 | Gauss |
| Mxy_D (Note 12) | X to Y magnetic matching drift | _ | _ | +/-5 | _ | % |
| Mx/yz_D (Note 12) | X/Y to Z magnetic matching drift | _ | _ | +/-20 | _ | % |
| TC | Temperature compensation | Bx, By, Bz | _ | 0 | _ | ppm/K |
| DNL (Note 12) | Differential nonlinearity | Bx, By, Bz | _ | +/-5 | _ | LSB |
| INL (Note 12) | Integral nonlinearity | Bx, By, Bz | _ | 0.1 | _ | %FSR |

Note:

12. Not subject to production test, verified by design/characterization.

Equation for parameter "X to Y magnetic matching":

$$M_{XY} = 100 * 2 * \frac{Sx - Sy}{Sx + Sy}$$
 [%]

Equation for parameter "X/Y to Z magnetic matching":

$$M_{X/YZ} = 100 * 2 * \frac{Sx + Sy - 2 * Sz}{Sx + Sy + 2 * Sz}$$
 [%]



Application Information

1 General Description

As described on the block diagram the three vector components of the magnetic flux density (BX, BY and BZ) applied to the IC are sensed through the sensor front-end. The 3-axies Hall signals are generated at the Hall plates and amplified. The analog front-end is based on a fully differential analog chain with offset cancellation technique. The conditioned analog signals are converted through an ADC and provided to a DSP block for further processing. The DSP stage is a customized finite state machine whose major function consists of signal conditioning of the XYZ Hall signals. Offset and sensitivity drift compensation are using the calibrated internal temperature sensor to improve the sensor's accuracy.

These 3D linear Hall measurements can be read out to the communication bus master. The supported communication protocols are I²C, where the AH4930Q is a slave on the bus. Upon read-back, it is then up to the microcontroller to process the measurement data in order to achieve more complex position sensing functionality required by the application.

2 Functional Description

The AH4930Q consists of three main function blocks containing:

- The power management system: containing a low-power oscillator, a fast oscillator, biasing, accurate reset, and undervoltage detection.
- The analog front-end: containing the HALL biasing, HALL sensing with multiplexers and an ADC. Furthermore, a temperature sensor is implemented.
- The FSM/DSP and I²C interface: containing the Finite State Machine and DSP to process data, I²C interface to communicate to master, register file to store parameters and I/O pads.

2.1 Power Management

The power management unit provides the conversion modes control in the IC, a power-on reset function and fast/low-power oscillators as clock sources.

It also handles the startup procedure.

- · When startup this unit:
 - provides an accurate reset/UVLO detector, activates the biasing, and fast/low oscillator.
 - the applied voltage level on SDA pin must be set to high for I²C mode.
 - let sensor enter power-down mode (also can be configured via I²C interface).

Note: 13. The sensor enters the power-down mode by default after power-up.

- After AH4930Q re-configured to one of the operating modes a measurement cycle is performed periodically including:
 - qualifies reset/UVLO condition, starts the internal biasing and enables the fast oscillator.
 - enables the HALL biasing and the measurements of the three HALL probe channels sequentially including temperature.
 - enters the configured mode again.

Only if the supply voltage is high enough to be above V_{UVLO} measurements are executed, otherwise the reset circuit will halt the state machine until the supply level is reached and continues its operation. The functions are also restarted if a power-on reset event occurs.

2.2 Analog Front-End (Signal Path)

The sensing part of analog front-end performs the measurements of the magnetic field in X, Y and Z direction. Each X, Y and Z-HALL data is consecutively output to a multiplexer, which is then connected to an ADC. The temperature is determined prior to the three HALL channels to compensate sensitivity drift and output as sensed junction temperature.

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2.3 Wake-Up Function

When upper and lower comparison threshold for each of the three magnetic channels (X/Y/Z) of wake-up function and wake-up enable are set, each component of the applied field is compared to the lower and upper threshold. Whenever one of the results is above or below these thresholds, an interrupt pulse /INT is generated. The sensor informs the microcontroller by asserting an interrupt for a certain magnetic field strength change. Only when all components of the magnetic field stay within the envelope, no interrupt signal will be provided. Note that the /INT can also be inhibited during I²C activities to avoid activated collision. A wake-up interrupt /INT is the logical OR among all wake-up interrupt envelopes of the three channels. The wake-up threshold levels will be XYZ_H/L[10:0]*2 Gauss when wake-up high/low threshold and wake-up enable are set.

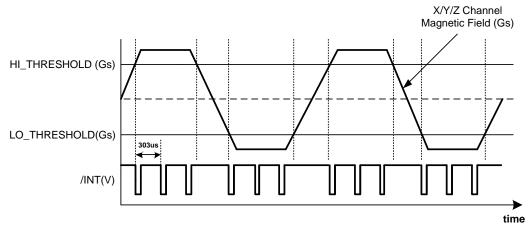


Figure 3. Wake-Up Function

3 Measurements

Below calculations of the magnetic flux and temperatures with 12 bit/8 bit are shown.

3.1 Calculation of the Magnetic Flux

The AH4930Q provides the Bx, By and Bz signed values based on Hall probes calculated in 2's complement. The magnetic flux values can be found in the Bx/By/Bz registers of register table. A generic example is calculated next.

Table 1 Conversion Table for 12 Bit

| | MSB Bit11 | Bit10 | Bit9 | Bit8 | Bit7 | Bit6 | Bit5 | Bit4 | Bit3 | Bit2 | Bit1 | LSB Bit0 |
|------|--------------|-------|------|------|------|------|------|------|------|------|------|-------------|
| | -2048 | 1024 | 512 | 256 | 128 | 64 | 32 | 16 | 8 | 4 | 2 | 1 |
| e.g. | 1 | 1 | 1 | 1 | 0 | 0 | 0 | 0 | 1 | 1 | 1 | 1 |

Example for 12 Bit read-out: 1111 0000 1111: -2048 + 1024 + 512 + 256 + 0 + 0 + 0 + 0 + 8 + 4 + 2 + 1 = -241 LSB

Calculation to Gs: -241 LSB x 1 Gs/LSB = -241Gs

Table 2 Conversion Table for 8 Bit

| | MSB Bit11 | Bit10 | Bit9 | Bit8 | Bit7 | Bit6 | Bit5 | Bit4 |
|------|--------------|-------|------|------|------|------|------|------|
| | -128 | 64 | 32 | 16 | 8 | 4 | 2 | 1 |
| e.g. | 0 | 1 | 0 | 0 | 1 | 1 | 0 | 1 |

Example for 8 Bit read-out: 0100 1101: 0 + 64 + 0 + 0 + 8 + 4 + 0 + 1 = 77 LSB

Calculation to Gs: 77 LSB x 16 Gs/LSB = 1232 Gs



3.2 Calculation of the Temperature

The AH4930Q also provides the temperature measurement based on a bandgap reference circuit. The temperature value can be found in two registers of register table (register 3H for the MSBs, register 6H for the LSBs).

The temperature is a signed value calculated in 2's complement but it will not provide 8 bit read-out. Examples with 12 bit are as follows.

Table 3 Conversion Table for 12 Bit

| | MSB Bit11 | Bit10 | Bit9 | Bit8 | Bit7 | Bit6 | Bit5 | Bit4 | Bit3 | Bit2 | Bit1 | LSB Bit0 |
|------|--------------|-------|------|------|------|------|------|------|------|------|------|-------------|
| | -2048 | 1024 | 512 | 256 | 128 | 64 | 32 | 16 | 8 | 4 | 2 | 1 |
| e.g. | 0 | 0 | 0 | 0 | 0 | 1 | 1 | 0 | 1 | 0 | 1 | 0 |

Example for 12 bit read-out: 0000 0110 1010: 0 + 0 + 0 + 0 + 0 + 64 + 32 + 0 + 8 + 0 + 2 + 0 = 106 LSB

Calculation to temperature in degrees Celsius: 106 LSB x 1°C/LSB = 106°C (Binary code is the temperature value)

4 I²C Interface

The AH4930Q uses Inter-Integrated Circuit (I²C) as communication interfaces with the microcontroller.

The I²C-compatible two-wire serial interface provides access to the programmable functions and registers on the device. This protocol uses a two-wire interface for bi-directional communications between the devices connected to the bus. The two interface lines are the serial data line (SDA) and the serial clock line (SCL). Every device on the bus is assigned a unique address and acts as either a master or a slave. AH4930Q can only be a slave in this sensor application.

4.1 I2C Interface Description

The I^2C interface has two main functions in AH4930Q: configuring the sensor and receiving measurement data. Additionally, I^2C also handles the interrupt via SCL pin.

- The I²C interface requires two pins:
 - A serial clock (SCL) input pin. The clock is generated by the microcontroller.
 - A serial data pin (SDA) for in & output (open drain). The microcontroller always initiates and concludes the transaction.
- The data transmission order is Most-Significant Bit (MSB) first, Last-Significant Bit (LSB) last. Data bytes start always with the register address 00H.
- The interface can be accessed in any power mode, even in power-down mode.
- The values of all three axis (Bx, By, Bz) are put in separate registers for I²C read-out. After a power-on reset, these registers will read zero.
- Power-on reset initializes registers to default values and UVLO levels which only affects the ADC supply level during a conversion will lead to an ADC cycle resetting only, and the register values will remain as they are. Deep reset levels could result in internal registers corruption and will lead into a full reset to make default values to be reloaded, and a power-on cycle will be executed.
- A full reset can be triggered via I²C by sending the address 0x00 to all slaves (sensors). A two-bit frame counter allows to check if the power unit did not initiate a measurement cycle, or the ADC did not complete a new measurement which means the frame counter does not get incremented.
- An I²C write transaction writing all four write registers requires a start condition, 45 bits transfer and a stop condition. At 400 kbit/s this means approximately 113µs.
- An I²C read transaction reading the top seven registers (from register 00h to 06h) requires a start condition, 81 bits transfer and a stop condition. At 400 kbit/s this means approximately 203µs.

The interface can be operated in I²C fast mode (400 kBit/sec max) and is up to 1 Mbit/sec in case the electrical setup of the bus can meet AH4930Q electrical characteristics requirement. The allowed max clock rate above 400kHz has to be defined on demand given a specific electrical setup depending on the parasitic load of the bus line

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4.2 I²C Format Description

I²C transaction is always initiated (with a start condition) and ended (with a stop condition) by the master (microcontroller). During a start or stop condition the SCL line must stay high. The I²C transaction frame consists of the start condition, one addressing byte which corresponds to the slave address (sensor number), the data transfer bytes (writing to slave or reading from slave) and finally the stop condition. Addressing and data transfer bytes are always followed by an acknowledge (ACK) bit. During the addressing and the data transfer, bit transitions occur with the SCL line at low. If no error occurs during the data transfer, the ACK bit will be driven low. If an error occurs, the ACK bit will be driven high as NACK.

The I²C protocol uses a standard 7-bit address followed by data bytes to be sent or received. AH4930Q does not support 12-bit addressing or any sub-addressing, so each start condition always begins with writing the address, followed by reading (or writing) the first byte of the bitmap and continues with reading (or writing) the next byte until all bytes are read (or written) or the transaction is simply terminated by a stop condition. The basic initiator for the protocol is the falling SDA edge when SCL is high as is called a start condition.

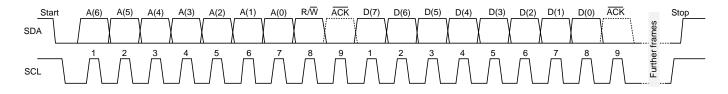


Figure 4. General I²C Format

The default setting after startup for a read operation is shown. In order to set SDA must be pulled high during power-up. To set the address the high or low level must be kept 260µs typically after supplying the sensor.

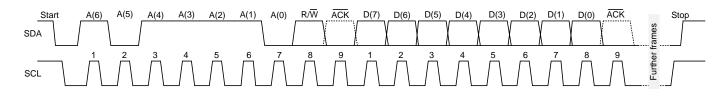


Figure 5. Read Example with Default Setting (Read = BD; Write = BC)

4.3 Communication Examples

An example of a read transaction is shown in Figure 6. The master generates a start condition followed by the addressing to sensor number (1011110B) and the read bit (1B). The slave responds with an ACK for the addressing and outputs the first register (register 0H), which corresponds to the Bx value (01011101B). The master responds with an ACK once the register is read. The slave outputs the second register (register 1H), which corresponds to the By value (11111001B). The master responds with an ACK and since no more information is required the master generates the stop condition.

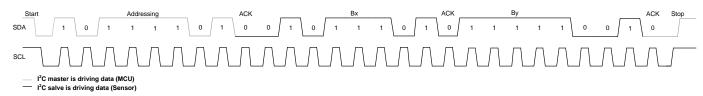


Figure 6. I²C Read Transaction Example



An example of a typical write transaction at startup is shown in Figure 7. The AH4930Q is by default configured in power-down and Bx, By, Bz values are zeros. To start Bx, By, Bz conversions at a given update rate the configuration has to be changed to other power mode. In low-power mode example, the master generates a start condition followed by the sensor number (1011110B) and a write bit (0B). The slave responds with an ACK. The master continues the transmission writing 00000000B at the first writing register (a reserved register). The slave responds with an ACK. The master writes 0000 0101B in the second writing register (configuration register MOD1). The slave responds with an ACK and since no more data need to be written the master finishes the transaction with a stop condition. With this configuration the interrupt pulse bit is enabled (MOD1 register = xxxx xx1xxB) and the low-power mode bit is enabled (MOD1 register = xxxx xxxx1B). Every 10ms a Bx, By, Bz conversion will be measured and once the conversion is completed an interrupt pulse will be sent to master. The master can then read the Bx, By and Bz registers.

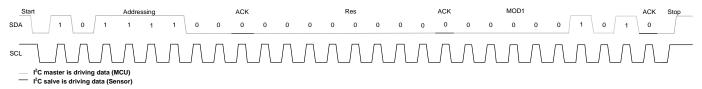


Figure 7. I²C Write Transaction Example

Note: 14. AH4930Q requires 4 write registers be completely written to activate function change.

5 Power-Up, Sensor Initialization and Access Modes

At power-up the AH4930Q is initialized with the default configuration and enters power-down mode (default mode). The power-down mode allows master to access the registers to read (default values) or write (for configuration), but no magnetic field nor temperature values are measured.

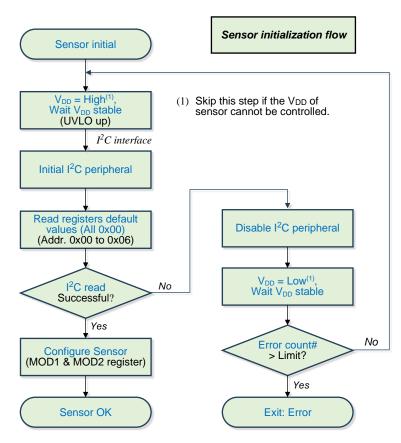
To start measurements, one of the following modes must be configured:

- Continuous (Fast) mode (FSM)
- Low-power mode (LPM)
- Ultra low-power mode (ULPM)
- · Master controlled mode (MCM)
- · Master controlled low-power mode (programmed by master)

These modes are described in the following sections.



5.1 Power-Up Sequence and Sensor Initialization



5.2 Power-Up and Power-Down Mode

After power-up, the sensor captures the voltage applied on SDA pin for 260µs to fix I²C address. The voltage level on SDA must be high during power-up. For a short period of time the power consumption increases to a larger current. During this short period all functional blocks are active, but no magnetic measurement nor temperature measurement takes place. After AH4930Q enters the "power-down mode" all functional blocks are off and wait for other configurations to leave power-down mode to start measurements.

Note: 15. For startup the sequence in Section 5.1 is strongly recommended.

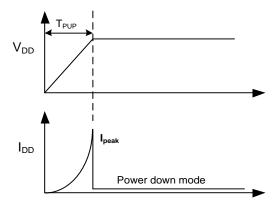


Figure 8. Current Consumption During Power-Up



5.2.1 Power-Down Mode (PDM)

To enter power-down mode, please set in write-register 1H[1] = 0 (FAST = 0) and set 1H[0] = 0 (LOW = 0).

5.3 Continuous (Fast) Mode (3.3kHz) (FSM)

Settings: INT = 1, FAST = 1, LOW = 0, LP = 0 (byte settings [hex] = 00, x6, xx, xx)

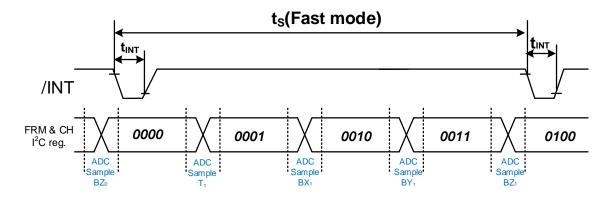


Figure 9. Fast Mode in Relation to /INT Output

To optimize the read-out the sample of the last conversion can be read while the next conversion is being performed. The I²C read-out speed can be faster or slower than ADC conversion speed depending on the system requirement. Trading between magnet changing speed and system read-out need should be considered.

Notes:

- 16. This mode requires an I²C fast mode+ 1MHz I²C clock to be used to read the data fast enough if system has the need.
- 17. User is recommended to assert I²C read transaction as soon as possible after previous /INT assertion to avoid I²C transaction being interfered by /INT.

5.4 Low-Power Mode (83.3Hz) (LPM)

Settings: INT = 1, FAST = 0, LOW = 1, LP = 1 (byte settings [hex]: 00, x5, xx, 4x)

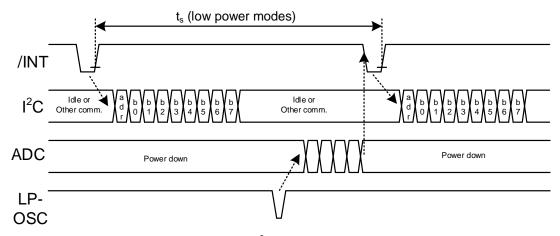


Figure 10. Synchronous, Low-Power I²C Read-Out Using an /INT Wake-Up Pulse

In this low-power mode the sensor goes into nearly power-down mode until internal LOSC counter counts up to wake up AH4930Q to perform the next conversion. Once the conversion is completed the interrupt line will be pulled low (if /INT is activated). From above the low-power modes the time window to read out all registers after the rising edge of the interrupt pulse is equal to one over the sample rate of this low-power mode minus the conversion time.



5.4.1 Ultra Low-Power Mode (10Hz) (ULPM)

Settings: INT = 1, FAST = 0, LOW = 1, LP = 0 (byte settings [hex]: 00, x5, xx, 0x)

In this mode a very low power combination of ultra low-power consumption and internal regular wake-up function is reached. The basic function is similar to low-power mode, but low-power mode has higher current consumption than ultra low-power mode.

5.5 Master Controlled Mode (Variable to fmax = 3.3kHz) (MCM)

Settings: INT = 0/1, FAST = 1, LOW = 1 (byte settings: 00, x7, xx, xx)

- · One measurement cycle is performed, and interrupt is asserted, and the measurement data is available for read-out in the registers.
- The sensor is waiting for read-out and no other measurements are done.
- Once the master performs a read-out a new measurement cycle is internally initiated by the sensor and new values will be stored in the registers. If no further read-out takes place no new measurement cycle is initiated. Periodic read-out of I²C causes a re-run of a new measurement cycle. It only needs to be ensured that the read-out time is larger than the time for the I²C read frame plus the sensor conversion time.

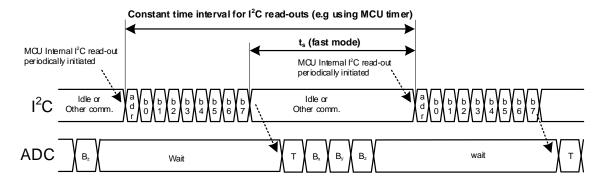


Figure 11. Synchronous, Fast I²C Access Using a Periodic I²C Read-Out

In the mode the interrupt output could be activated and used as well. This will provide the fastest and safest way to read out all axis data with a 12-bit resolution value, as to be shown next. This allows a read-out of the sensor to the master (μ C) using an interrupt service routine. The sample rate is now determined by the ADC conversion time plus the I²C read-out time only and fully avoids the read of inconsistent values.

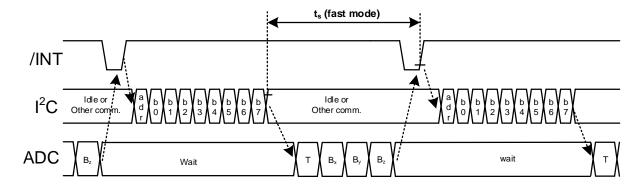


Figure 12. Synchronous, Fast I²C Access Using an /INT Trigger for I²C Read-Out

18. If user writes registers to set MCM with interrupt enabled and continues to write WU registers, 1 /INT pulse might be omitted if CA bit is set. User can directly read for the first magnetic field data before next /INT asserted.

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Note



6 Power Supply Considerations

The power supply and its circuitries should be designed to ensure a stable startup and sensor initialization as well as a stable operation for correct I^2C transaction. The sensor can be supplied by the same supply used by the microcontroller or by an alternative supply with switch. The usage of a microcontroller output pin is considered an alternative power supply. The following considerations must be covered in any case:

- The voltage on bus pins must not be higher than voltage on the supply pins.
- The supply has to cope with the specified DC currents of the sensor and AC current peaks from digital logic operation (from bus interface and from internal sensor logic).
- Inrush current of the supply buffer capacitor must be considered by dimensioning of the power supply.
- The sensor does not have any internal overvoltage protection nor reverse voltage protection
- The supply power-up ramp is recommended to be as 5.2 specifies.

7 Bus Configuration with Multiple Sensors

AH4930Q can be programmed as multiple slaves (sensors, up to 4) to a master in a bus configuration. The slave addresses are configured sequentially at startup. Each slave requires a dedicated supply line, and therefore the master must provide enough I/O pins capable of driving up to 6mA DC in each line.

7.1 Configuration with Multiple Slaves in I²C Interface

AH4930Q is powered up together with the whole system startup, while AH4930Q remains powered down. Within the first 260µs after the power-up, AH4930Q reads the voltage applied on SDA pin and the voltage level on SDA must be set to high as Figure 13 then the address is set to "1" (default case with open-drain configuration). This configuration remains fixed till the next power-down or reset. Once the slaves are to be configured to multiple sensors as below diagram, the master can access to read or write any slave by addressing them according to Table 4.

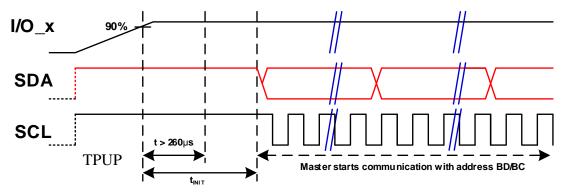


Figure 13. Startup Sequence and Timing for Bus Configuration

Note: 19. It is also possible to configure multiple slaves by changing the IICAddr bits in the write register MOD1 independently of the SDA pin at startup.

Table 4 Addressing with Multiple Slaves

| Clave | CDA Din et Dewer Un | IICAddr I | Bits (Bin) | Re | ad | Write | | |
|-------|---------------------|-----------|------------|-----------|-----|-----------|-----|--|
| Slave | SDA Pin at Power-Up | Default | Bus | Bin | Hex | Bin | Hex | |
| 0 | High (1) | 00 | 11 | 1001 0101 | 95 | 1001 0100 | 94 | |
| 1 | High (1) | 00 | 10 | 1001 1101 | 9D | 1001 1100 | 9C | |
| 2 | High (1) | 00 | 01 | 1011 0101 | B5 | 1011 0100 | B4 | |
| 3 | High (1) | 00 | 00 | 1011 1101 | BD | 1011 1100 | ВС | |

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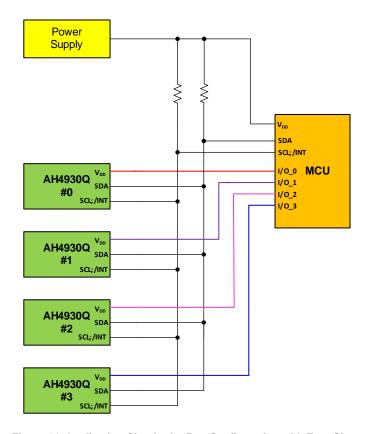


Figure 14. Application Circuits for Bus Configuration with Four Slaves

8 I²C and Registers

The AH4930Q includes several registers that can be accessed via I^2C to read data as well as to write and configure settings. There are 16 read registers and 16 write registers. All registers should be accessed from 0H either read or write.

8.1 Registers Overview

A register bitmap overview is presented in the tables below. Read registers from 0H to 6H can only be read and cannot be modified via write transactions while write registers 0H to 4H can only be written and cannot be read out via read transactions. 7H to FH can be both written in and read out.



8.1.1 Read Registers

The I²C registers can be read at any time, starting always from address 0H and as long as the master sends a clock signal (SCL). It is recommended to use the sensor interrupt to read data after an interrupt pulse. This can avoid reading inconsistent values, especially when running the fast mode. Additionally, several flags can be checked to ensure the data values are consistent and the ADC was not running at the time of read-out.

| 7 6 | 5 | 4 Bx[11 By[11 Bz[11 | | 2 | 1 | 0 | Comment |
|------|----------------------|----------------------------|---|---|---|---|---|
| Te | | By[11 | | | | | D., MCD[44,4] |
| Te | | | 1:4] | | | | Bx MSB[11:4] |
| Te | | Bz[11 | | | | | By MSB[11:4] |
| Те | | | 1:4] | | | | Bz MSB[11:4] |
| | mp[11:8] | | FRN | / [1:0] | СН | l[1:0] | Temp MSB[11:8], Frame number, CH number |
| I | 3x[3:0] | By[3:0] | | | | | Bx LSB[3:0], By LSB[3:0] |
| Rsvo | | PD | | Bz[3 | :0] | PD, Bz LSB[3:0] | |
| | Temp[7:0] | | | | | | Temp LSB[7:0] |
| | WU_XH[10:3] | | | | | | WU_X high threshold[10:3] |
| | | WU_XL | [10:3] | | | | WU X low threshold[10:3] |
| | | WU_YH | 1[10:3] | | | | WU_Y high threshold[10:3] |
| | | WU_YL | [10:3] | | | | WU Y low threshold[10:3] |
| | | WU_ZH | l[10:3] | | | | WU_Z high threshold[10:3] |
| | WU_ZL[10:3] | | | | | WU Z low threshold[10:3] | |
| Rsvd | | XL[2:0] | XH[2:0] | | | | WU X high/low threshold[2:0] |
| Rsvd | | YL[2:0] | | | YH[2:0] | | WU Y high/low threshold[2:0] |
| Rsvd | | ZL[2:0] | | | ZH[2:0] | | WU Z high/low threshold[2:0] |
| | Rsvd Rsvd Rsvd | Bx[3:0] Rsvd Rsvd Rsvd | Bx[3:0] Rsvd PD Temp WU_XH WU_XL WU_YH WU_YL WU_ZL Rsvd XL[2:0] Rsvd YL[2:0] | Bx[3:0] Rsvd PD Temp[7:0] WU_XH[10:3] WU_XL[10:3] WU_YH[10:3] WU_YL[10:3] WU_ZH[10:3] WU_ZL[10:3] Rsvd XL[2:0] Rsvd YL[2:0] | Bx[3:0] By[3 Rsvd PD Bz[3 Temp[7:0] WU_XH[10:3] WU_XL[10:3] WU_YH[10:3] WU_YL[10:3] WU_ZH[10:3] WU_ZL[10:3] Rsvd XL[2:0] X Rsvd YL[2:0] X | Bx[3:0] Rsvd PD Bz[3:0] Temp[7:0] WU_XH[10:3] WU_YL[10:3] WU_YL[10:3] WU_ZL[10:3] Rsvd XL[2:0] XH[2:0] Rsvd YL[2:0] YH[2:0] | Bx[3:0] By[3:0] Rsvd PD Bz[3:0] WU_XH[10:3] WU_XL[10:3] WU_YL[10:3] WU_YL[10:3] WU_ZL[10:3] WU_ZL[10:3] Rsvd XL[2:0] XH[2:0] Rsvd YL[2:0] YH[2:0] |

*) Bx[11:4]: Bx MSB[11:4]

By(1H)

*) By[11:4]: By MSB[11:4]

Bz(2H)

*) Bz[11:4]: Bz MSB[11:4]

Temp(3H)

*) Temp[11:8]: Temp MSB[11:8]
*) FRM[1:0]: Frame number. Check if bits have changed in consecutive conversion runs.

Increments at every update rate, once a T/X/Y/Z conversion is completed

*) CH[1:0]: Channel number.

If "00" no conversion (internal power-down) or temperature conversion started (but value not yet stored in the register)

If "01" x-direction conversion ongoing

If "10" y-direction conversion ongoing

If "11" z-direction conversion ongoing

Bx2y2(4H)

*) Bx[3:0]: Bx LSB[3:0]

*) By[3:0]: By LSB[3:0]

*) Bz2[4]: PD: Power-down flag. Must be "1" at read-out.

If "1", Bx, By, Bz and Temp conversion completed.

If "0", Bx, By, Bz and Temp conversion running

*) Bz[3:0]: Bz LSB[3:0]

Temp2(6H)

*) Temp[7:0]: Temp LSB[7:0]

WU(7H~FH)

*) WU_XH[10:0]: Wake-up X high threshold[10:0]. Wake-up threshold level = WU_XH[10:0] x 2 gauss.

WU_XL[10:0]: Wake-up X low threshold[10:0]. Wake-up threshold level = WU_XL[10:0] x 2 gauss.

 $WU_YH[10:0]$: Wake-up Y high threshold[10:0]. Wake-up threshold level = $WU_YH[10:0] \times 2$ gauss.

WU_YL[10:0]: Wake-up Y low threshold[10:0]. Wake-up threshold level = WU_YL[10:0] x 2 gauss.

 $WU_ZH[10:0]$: Wake-up Z high threshold[10:0]. Wake-up threshold level = $WU_ZH[10:0] \times 2$ gauss.

WU_ZL[10:0]: Wake-up Z low threshold[10:0]. Wake-up threshold level = WU_ZL[10:0] x 2 gauss.

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8.1.2 Write Registers

Registers will be written starting always from address 0H and as many registers as long as the master generates a clock signal (SCL).

| Write Registers | | | | | | | | | |
|-----------------|---|-------------|------|---------|--|---------------------------|------------------------------|------------------------------|--------------------------------|
| Bit | 7 | 6 | 5 | 4 | 3 | 2 | 1 | 0 | Comment |
| Rsvd(0H) | Rsvd | | | | | Reserved | | | |
| MOD1(1H) | Rsvd IICAddr[1:0] WUE Rsvd INT FAST LOW | | | LOW | IICAddr, Wake-up enable, INT, Continuous (FAST mode), LOW power mode | | | | |
| Rsvd(2H) | Rsvd R | | | | | Reserved | | | |
| MOD2(3H) | Rsvd | LP | Rsvd | CA | Rsvd Low Po | | | | Low Power, Collision Avoidance |
| Rsvd(4H) | Rsvd | | | | | Reserved | | | |
| Rsvd(5H) | Rsvd | | | | | Reserved | | | |
| Rsvd(6H) | Rsvd Reserved | | | | | Reserved | | | |
| WU_XH(7H) | WU_XH[10:3] WU_X high threshold[10:3] | | | | | WU_X high threshold[10:3] | | | |
| WU_XL(8H) | WU_XL[10:3] WU X low thr | | | | | WU X low threshold[10:3] | | | |
| WU_YH(9H) | WU_YH[10:3] | | | | | WU_Y high threshold[10:3] | | | |
| WU_YL(AH) | WU_YL[10:3] | | | | | WU Y low threshold[10:3] | | | |
| WU_ZH(BH) | WU_ZH[10:3] WU_Z | | | | | WU_Z high threshold[10:3] | | | |
| WU_ZL(CH) | WU_ZL[10:3] | | | | | WU Z low threshold[10:3] | | | |
| WU_XLSB(DH) | Rsv | ⁄d | | XL[2:0] | XH[2:0] | | WU X high/low threshold[2:0] | | |
| WU_YLSB(EH) | Rsv | ⁄d | | YL[2:0] | YH[2:0] | | WU Y high/low threshold[2:0] | | |
| WU_ZLSB(FH) | Rsv | svd ZL[2:0] | | | | ZH[2:0] | | WU Z high/low threshold[2:0] | |

MOD1(1H)

- *) IICAddr[1:0]: I²C Address bits: Bits can be set to "00", "01", "10" or "11" to define the slave address in bus configuration
- *) WUE: Wake-up enable:
 - If "0" disable wake-up function
 - If "1" enable wake-up function
- *) INT: Interrupt pad enabled: If "1" INT (interrupt pulse) enabled (default).
 - If "0" INT (interrupt pulse) disabled
- *) FAST: Continuous (Fast) mode
 - If "1" continuous mode enabled
 - If "0" continuous mode disabled
- *) LOW: Low-power mode
 - If "0" disabled
 - If "1" enabled

MOD2(3H)

- *) LP: Low-power period
 - If "0" period is 83ms (ultra low-power period) If "1" period is 10ms
- *) CA: Collision avoidance.
 - If "0" /INT will be asserted anyway if INT is set to "1"
 - If "1" /INT will be asserted only when I2C bus is idle if INT is set to "1"

WU(7H~FH)

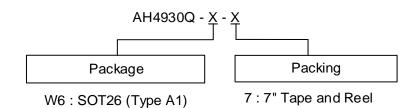
- *) WU_XH[10:0]: Wake-up X high threshold[10:0]. Wake-up threshold level = WU_XH[10:0] x 2 gauss.
 - WU_XL[10:0]: Wake-up X low threshold[10:0]. Wake-up threshold level = WU_XL[10:0] x 2 gauss.
 - WU_YH[10:0]: Wake-up Y high threshold[10:0]. Wake-up threshold level = WU_YH[10:0] x 2 gauss. WU_YL[10:0]: Wake-up Y low threshold[10:0]. Wake-up threshold level = WU_YL[10:0] × 2 gauss.
 - WU_ZH[10:0]: Wake-up Z high threshold[10:0]. Wake-up threshold level = WU_ZH[10:0] x 2 gauss.
- WU_ZL[10:0]: Wake-up Z low threshold[10:0]. Wake-up threshold level = WU_ZL[10:0] x 2 gauss.

20. Rsvd means reserved. All reserved bits must set to 0.

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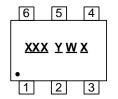


| Orderable Part Number | Package Code | Package | Packing | | |
|-----------------------|--------------|-----------------|---------|-------------|--|
| Orderable Fait Number | rackage code | rackaye | Qty. | Carrier | |
| AH4930Q-W6-7 | W6 | SOT26 (Type A1) | 3,000 | Tape & Reel | |

Marking Information

SOT26 (Type A1)

(Top View)



XXX: Identification Code

Y : Year 0 to 9 (ex: 5 = 2025) W : Week : A to Z : week 1 to 26; a to z : week 27 to 52; z represents

a to z : week 27 to 52; z represents week 52 and 53

X : Internal Code

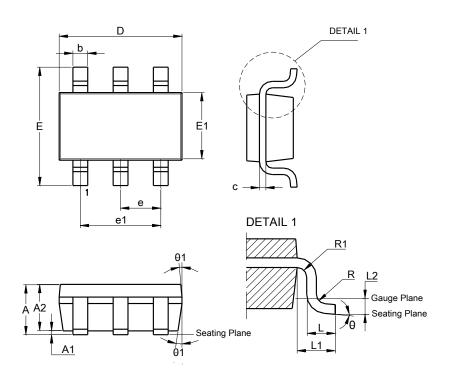
| Orderable Part Number | Package | Identification Code |
|-----------------------|-----------------|---------------------|
| AH4930Q-W6-7 | SOT26 (Type A1) | V2Q |



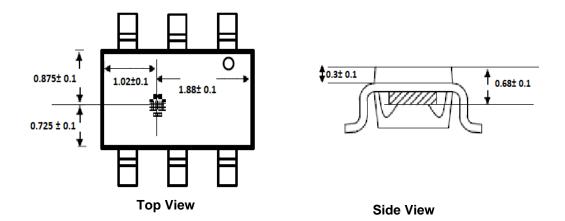
Package Outline Dimensions

Please see http://www.diodes.com/package-outlines.html for the latest version.

SOT26 (Type A1)



| SOT26 (Type A1) | | | | | |
|----------------------|----------|------|------|--|--|
| Dim | Min | Max | Тур | | |
| Α | | 1.45 | | | |
| A1 | 0.00 | 0.15 | | | |
| A2 | 0.90 | 1.30 | 1.15 | | |
| b | 0.30 | 0.50 | | | |
| С | 0.08 | 0.22 | | | |
| D | 2.90 BSC | | | | |
| Е | 2.80 BSC | | | | |
| E1 | 1.60 BSC | | | | |
| е | 0.95 BSC | | | | |
| e1 | 1.90 BSC | | | | |
| L | 0.30 | 0.60 | 0.45 | | |
| L1 | 0.60 REF | | | | |
| L2 | 0.25 BSC | | | | |
| R | 0.10 | | | | |
| R1 | 0.10 | 0.25 | | | |
| θ | 0° | 8° | 4° | | |
| θ1 | 5° | 15° | 10° | | |
| All Dimensions in mm | | | | | |



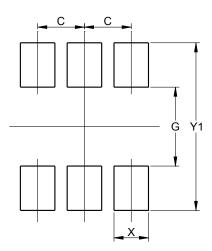
Sensor Location (Unit: mm)



Suggested Pad Layout

Please see http://www.diodes.com/package-outlines.html for the latest version.

SOT26 (Type A1)



| Dimensions | Value (in mm) |
|------------|------------------|
| С | 0.950 |
| G | 1.600 |
| Х | 0.700 |
| Y | 0.900 |
| Y1 | 3.400 |

Mechanical Data

- Moisture Sensitivity: Level 1 per J-STD-020
- Terminals: Finish Matte Tin Plated Leads, Solderable per MIL-STD-202, Method 208 @3
- Weight: 0.016 grams (Approximate)



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